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(54) **SCANNING PROBE MICROSCOPE**

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CPC ***G01Q 10/06*** (2013.01); *G01Q 60/30* (2013.01)

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See application file for complete search history.

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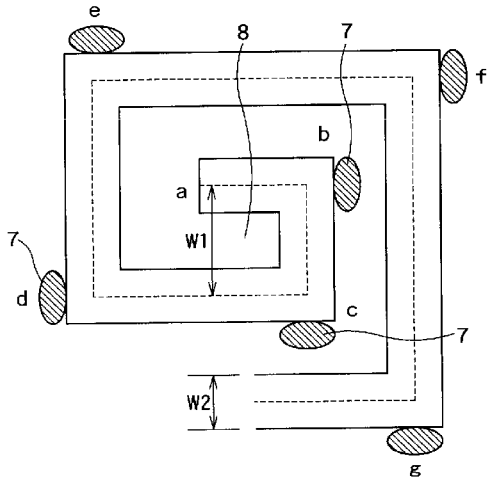
(57) **ABSTRACT**

A scanning probe microscope includes a stage on which a sample is mounted, a probe configured to measure a characteristic of the sample, and a controller configured to move the probe and the stage relative to each other along a scanning trajectory during measurement of the characteristic of the sample. The scanning trajectory includes a plurality of linear segments, wherein each pair of adjacent linear segments form an angle that is 90 degrees or less.

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